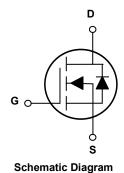




#### **Main Product Characteristics**

V <sub>(BR)DSS</sub>	800V		
R <sub>DS(ON)</sub>	1.56Ω		
I <sub>D</sub>	8A		





TO-220F

#### **Features and Benefits**

- Advanced MOSFET process technology
- Ideal for high efficiency switched mode power supplies
- Low on-resistance with low gate charge
- Fast switching and reverse body recovery



## **Description**

The GSFU8008 utilizes the latest techniques to achieve high cell density and low on-resistance. These features make this device extremely efficient and reliable for use in high efficiency switch mode power supply and a wide variety of other applications.

## **Absolute Maximum Ratings** (T<sub>C</sub>=25°C unless otherwise specified)

Parameter	Symbol	Max.	Unit
Drain-Source Voltage	V <sub>DS</sub>	800	V
Gate-to-Source Voltage	V <sub>GS</sub>	± 30	V
Continuous Drain Current, V <sub>GS</sub> @ 10V <sup>1</sup>	I <sub>D</sub> @ T <sub>C</sub> = 25°C	8	А
Continuous Drain Current, V <sub>GS</sub> @ 10V <sup>1</sup>	I <sub>D</sub> @ T <sub>C</sub> = 100°C	5.1	А
Pulsed Drain Current <sup>2</sup>	I <sub>DM</sub>	32	А
Single Pulse Avalanche Energy @ L=25mH	E <sub>AS</sub>	760	mJ
Avalanche Current@ L=25mH	I <sub>AS</sub>	7.8	А
Power Dissipation <sup>3</sup>	P <sub>D</sub> @T <sub>C</sub> = 25°C	59	w
Linear Derating Factor	_	0.48	W/°C
Junction-to-Case <sup>3</sup>	R <sub>ejc</sub>	2.1	°C/W
Junction-to-Ambient (t ≤ 10s) <sup>4</sup>	_	62.5	°C/W
Junction-to-Ambient (PCB Mounted, Steady-State) <sup>4</sup>	$R_{ heta JA}$	40	°C/W
Operating Junction and Storage Temperature Range	T <sub>J</sub> T <sub>STG</sub>	-55 to + 150	°C





## **Electrical Characteristics** (T<sub>C</sub>=25°C unless otherwise specified)

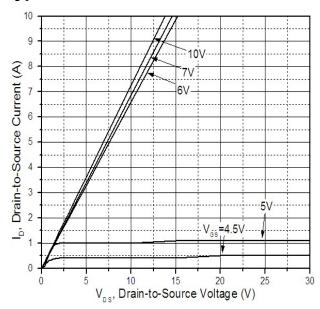
Parameter	Symbol	Conditions	Min.	Тур.	Max.	Unit	
Drain-to-Source Breakdown Voltage	$V_{(BR)DSS}$	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250μA	800	-	_	V	
Drain-to-Source Leakage Current	I <sub>DSS</sub>	V <sub>DS</sub> = 800V, V <sub>GS</sub> = 0V	-	-	1	μА	
		T <sub>J</sub> = 125°C	=	-	50		
Cata ta Cauraa Farruardi aalaara		V <sub>GS</sub> =30V	-	-	100	nA	
Gate-to-Source Forward Leakage	I <sub>GSS</sub>	V <sub>GS</sub> = -30V	-	-	-100		
Static Drain-to-Source On-	R <sub>DS (on)</sub>	V <sub>GS</sub> =10V, I <sub>D</sub> = 3.5A	-	1.32	1.56	Ω	
Resistance		T <sub>J</sub> = 125°C	=	2.38	-		
Gate Threshold Voltage	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2	3	4	1 .,	
	$V_{GS\ (th)}$	T <sub>J</sub> = 125°C	=	1.93	-		
Input Capacitance	C <sub>iss</sub>		-	1106	-	pF	
Output Capacitance	$C_{oss}$	$V_{GS} = 0V V_{DS} = 25V f$ = 1MHz	-	121	-		
Reverse transfer capacitance	$C_{rss}$		-	5.2	-		
Total Gate Charge	$Q_g$		-	24	-	nC	
Gate-to-Source Charge	$Q_{gs}$	$I_D = 8A, V_{DS} = 400V,$ $V_{GS} = 10V$	-	7.2	-		
Gate-to-Drain("Miller") Charge	$Q_{gd}$		-	9.7	-		
Turn-on Delay Time	$t_{d(on)}$		-	20	-	nS	
Rise Time	t <sub>r</sub>	$V_{GS}$ =10V, $V_{DS}$ =400V, $R_L$ =50 $\Omega$ ,	=	37	-		
Turn-Off Delay Time	$t_{d(off)}$	$R_{GEN}$ =25 $\Omega$ $I_{D}$ =8 $\Lambda$	=	59	-		
Fall Time	$t_f$		-	36	-		
Source-Drain Ratings and Charac	cteristics			1		•	
Parameter	Symbol	Conditions	Min.	Тур.	Max.	Unit	
Continuous Source Current (Body Diode)	Is	MOSFET symbol showing the integral reverse	-	-	8	А	
Pulsed Source Current (Body Diode)	I <sub>SM</sub>	p-n junction diode.	-	-	32	Α	
Diode Forward Voltage	$V_{SD}$	I <sub>S</sub> =8A, V <sub>GS</sub> =0V	-	0.74	1.4	V	
Reverse Recovery Time	t <sub>rr</sub>	T <sub>J=</sub> 25°C, I <sub>F</sub> =8A	-	968	-	ns	
Reverse Recovery Charge	$Q_{rr}$	d <sub>i</sub> /d <sub>t</sub> =100A/µs	-	5456	-	nC	

#### Notes

- 1. Calculated continuous current based on maximum allowable junction temperature.
- 2. Repetitive rating; pulse width limited by max. junction temperature.
- 3. The power dissipation P<sub>D</sub> is based on max. junction temperature, using junction-to-case thermal resistance.
- 4. The value of  $R_{\text{BJA}}$  is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with  $T_{\text{A}}$ =25°C



# **Typical Electrical and Thermal Characteristic Curves**



**Figure 1. Typical Output Characteristics** 

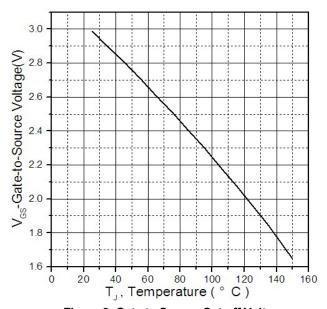


Figure 2. Gate to Source Cut-off Voltage

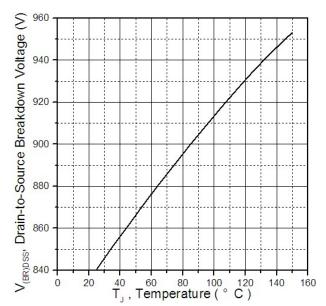


Figure 3. Drain-to-Source Breakdown Voltage Vs. Junction Temperature.

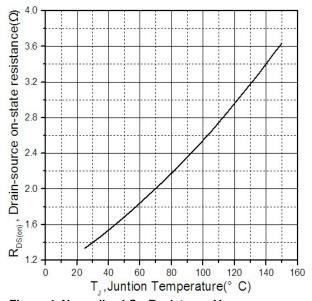


Figure 4. Normalized On-Resistance Vs. Junction Temperature



## **Typical Electrical and Thermal Characteristic Curves**

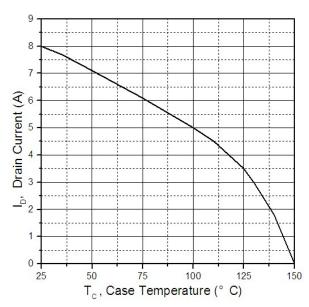


Figure 5. Maximum Drain Current Vs. Case Temperature

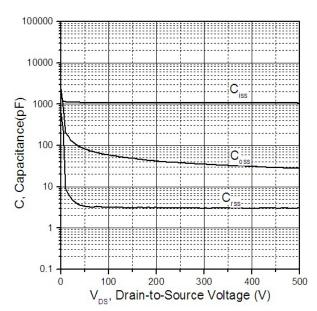


Figure 6. Typical Capacitance Vs. Drain-to- Source Voltage

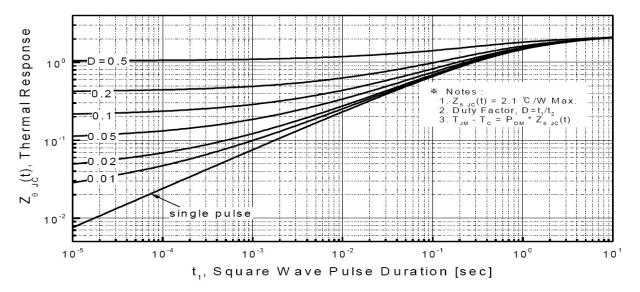


Figure 7. Maximum Effective Transient Thermal Impedance, Junction-to-Case



# **Test Circuit & Waveform**

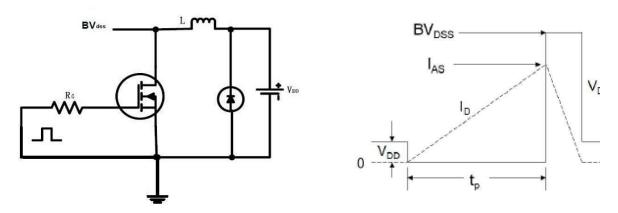


Figure 8. Unclamped Inductive Switching Test Circuit & Waveforms

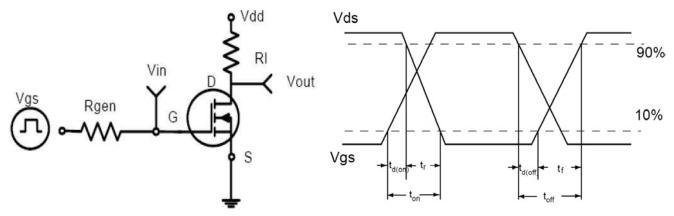


Figure 9. Resistive Switching Test Circuit & Waveforms

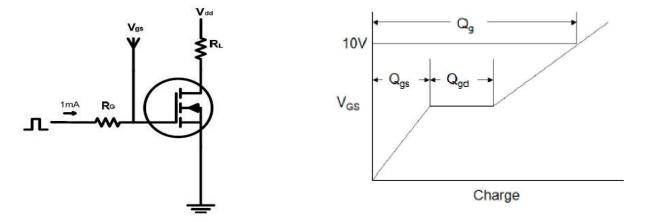
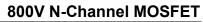


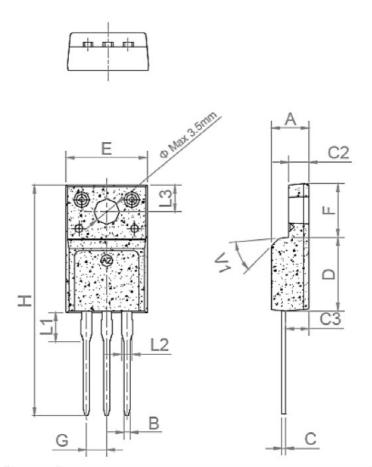
Figure 10. Gate Charge Test Circuit & Waveform





# **Package Outline Dimensions**

## **TO-220F**



Ref.	Dimensions						
	Millimeters			Inches			
	Min.	Typ.	Max.	Min.	Тур.	Max.	
Α	4.50		4.90	0.177		0.193	
В	0.74	0.80	0.83	0.029	0.031	0.033	
С	0.47		0.65	0.019		0.026	
C2	2.45		2.75	0.096	300	0.108	
C3	2.60		3.00	0.102		0.118	
D	8.80		9.30	0.346		0.366	
Е	9.80		10.4	0.386		0.410	
F	6.40		6.80	0.252		0.268	
G		2.54		0	0.1	8	
Н	28.0		29.8	1.102		1.173	
L1		3.63			0.143		
L2	1.14		1.70	0.045		0.067	
L3		3.30			0.130		
V1	8	45°	á	8	45°		